


<b>Search Notes</b> 	<b>Application/Control No.</b> 10561595	<b>Applicant(s)/Patent Under Reexamination</b> TSURU ET AL.
	<b>Examiner</b> YUBIN HUNG	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
382	166, 232,236,239,250,251	6/14/09	YH
375	240.03,240.2	6/14/09	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (USPGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB)	6/14/09	YH
Inventor/Assignee search (EAST/eDAN)	6/14/09	YH
ACM	6/14/09	YH
IEEE Explore	6/14/09	YH
SPIE	6/14/09	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	166,236,239	6/14/09	YH
375	240.03	6/14/09	YH

	/YUBIN HUNG/ Primary Examiner.Art Unit 2624
--	--